Application/Control No. Applicant(s)/Patent Under Reexamination 10/695,185 OKU ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Deborah Yee 1742 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α В US-С US-US-D Ε US-US-F G US-US-Н US-US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY 410017999A Ν 01-1998 Japan Kono, Masaaki et al 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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